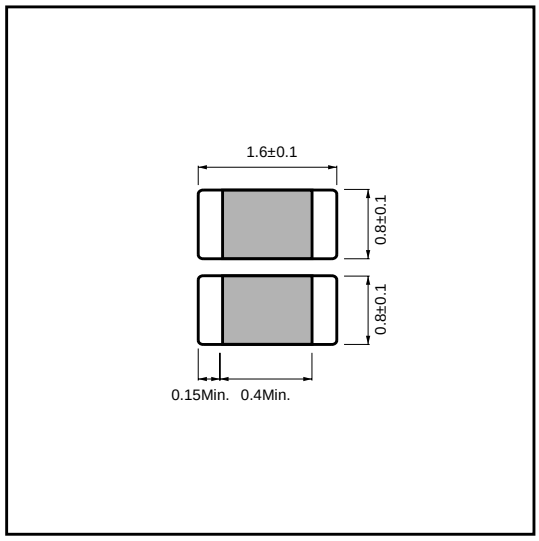
Multi-layer ceramic chip capacitors

MCH18 (1608 (0603) size, chip capacitor)

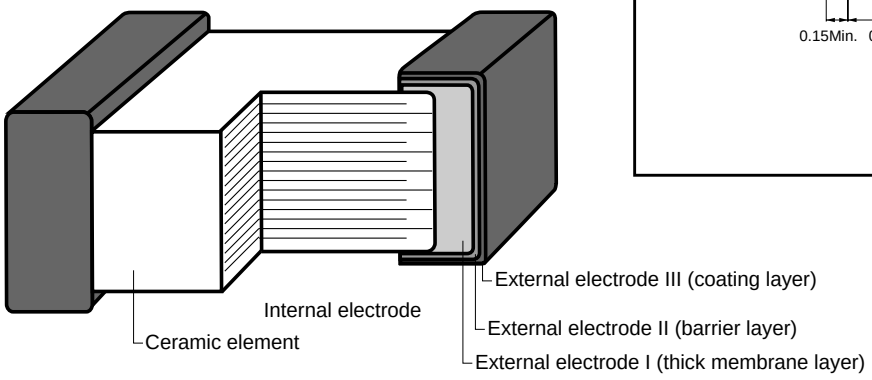
●Features

1) Small size (1.6 x 0.8 x 0.8 mm) makes it perfect for lightweight portable devices.
2) Comes packed either in tape to enable automatic mounting or in bulk cases.
3) Barrier layer and end terminations to improve solderability.
4) Solder-coated terminals offer superior solderability and resistance to soldering heat.

●External dimensions (Units : mm)



●Structure



●Product designation

Code	Product thickness	Packaging specifications	Reel	Basic ordering (pcs.)
K	0.8mm	Paper tape (width 8 mm, pitch 4 mm)	ϕ180mm (7in.)	4,000
L	0.8mm	Paper tape (width 8 mm, pitch 4 mm)	ϕ330mm (13in.)	16,000
C	0.8mm	Bulk case	-	15,000

Ree l(ϕ180,ϕ330mm) : compatible with EIAJ ETX-7001
Bulk case : according to EIAJ ET-7201A

Part No. — Packaging style

M	C	H	1	8	2	F	1	0	4	Z	K

Rated voltage

Code	Voltage
2	25V
3	16V
4	10V
5	50V

Capacitance-temperature characteristics				Nominal capacitance	Capacitance tolerance	
Code	EIA code	Operating temperature (ºC)	Temp. coefficient or percent change		Code	tolerance
A	C0G	- 55 to +125	0 ±30ppm / ºC	3-digit designation according to IEC	C	±0.25pF (0.5 ~ 5pF)
					D	±0.5pF (5.1 ~ 10pF)
					J	±5% (11pF or more)
C,CN	X7R	- 55 to +125	±15%		K	±10%
F,FN	Y5V	- 30 to + 85	+ 22%,- 82%		Z	+80%,-20%

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●Capacitance range

For thermal compensation

Part number.		MCH18
Capacitance(pF)	Temperature characteristics	A (C0G)
	Rated voltage (V) / Tolerance	50
0.5	C (± 0.25pF)	▨
0.75		▨
1		▨
1.1		▨
1.2		▨
1.3		▨
1.5		▨
1.6		▨
1.8		▨
2		▨
2.2		▨
2.4		▨
2.7		▨
3		▨
3.3		▨
3.6		▨
3.9		▨
4		▨
4.3		▨
4.7		▨
5		▨
5.1	D (± 0.5pF)	▨
5.6		▨
6		▨
6.2		▨
6.8		▨
7		▨
7.5		▨
8		▨
8.2		▨
9		▨
9.1		▨
10		▨
11	J (± 5%)	▨
12		▨
13		▨
15		▨
16		▨
18		▨
20		▨
22		▨
24		▨
27		▨
30		▨
33		▨
36		▨
39		▨
43		▨
47		▨
51		▨
56		▨
62		▨
68		▨
75		▨
82		▨
91		▨
100		▨

Part number.		MCH18
Capacitance (pF)	Temperature characteristics	A (C0G)
	Rated voltage (V) / Tolerance	50
110	J (± 5%)	▨
120		▨
130		▨
150		▨
160		▨
180		▨
200		▨
220		▨
240		▨
270		▨
300		▨
330		▨
360		▨
390		▨
430		▨
470		▨
510		▨
560		▨
620		▨
680		▨
750		▨
820		▨
910		
1,000		

▨ Product thickness(mm) 0.8 ± 0.1

Ceramic capacitors

High dielectric constant

Part number		MCH18								
Capacitance(pF)	Temperature characteristics	C(X7R)	CN(X7R)			F(Y5V)	FN(Y5V)			
	Rated voltage (V)	50	50	25	10	50	50	25	16	10
	Tolerance	K(±10%)	K(±10%)			Z(+80%, -20%)	Z(+80%, -20%)			
220 270 330		■								
390 470 560		■								
680 820 1,000		■				■				
1,200 1,500 1,800		■								
2,200 2,700 3,300		■				■				
3,900 4,700 5,600		■				■				
6,800 8,200 10,000 (0.01µF)		■	■			■				
12,000 15,000 18,000			■							
22,000 27,000 33,000			■	■		■				
39,000 47,000 56,000				■			■			
68,000 82,000 100,000 (0.1µF)				■ ■				■		
120,000 150,000 180,000					■					
220,000 270,000 330,000					■ ■				■	
390,000 470,000 560,000					■					■
680,000 1,000,000 (1µF) 1,200,000										■
1,500,000 1,800,000 2,200,000										

■ Product thickness (mm) 0.8 ± 0.1

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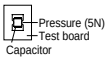
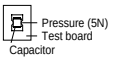
●Characteristics

Class 1 (For thermal compensation)

Item \ Temperature characteristics		A (C0G)	Test methods / conditions (based on JIS C 5102)
Operating temperature		- 55ºC ~ + 125ºC	————
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity. 1000pF or less Measurement frequency : 1± 0.1MHz Measurement voltage : 1± 0.1Vrms. Over 1000pF Measurement frequency : 1± 0.1kHz Measurement voltage : 1± 0.1Vrms.
Dissipation factor (tan δ)		100 / (400 + 20C)% or less (Less than 30 pF) 0.1% or less (30 pF or larger)	
Insulation resistance (IR)		10,000 MΩ or 500MΩ·μF, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 ± 5s.
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.
Temperature characteristics		Within 0 ± 30ppm / ºC	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20ºC and high temperature.
Terminal adherence		No detachment or signs of detachment.	Based on paragraph 8.11.2 Apply 5N (0.51 kg · f) for 10 ± 1s in the direction indicated by the arrow. 
Resistance to vibration	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the manner shown on the right, subjected to vibration (type A in paragraph 8.2), and measured 24 ± 2 hrs. later. 
	Rate of capacitance change	Must be within initial tolerance.	
	Dissipation factor (tanδ)	Must satisfy initial specified value.	
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature : 235 ± 5ºC Soldering time : 2 ± 0.5s
Resistance to soldering heat	Appearance	There must be no mechanical damage.	Based on paragraph 8.14 Soldering temperature : 260 ± 5ºC Soldering time : 5 ± 0.5s Preheating : 150 ± 10ºC for 1 to 2 min.
	Rate of capacitance change	± 2.5% or ± 0.25 pF, whichever is larger.	
	Dissipation factor (tanδ)	Must satisfy initial specified value.	
	Insulation resistance	10,000 MΩ or 500MΩ·μF , whichever is smaller	
	Withstanding voltage	The insulation must not be damaged.	
Temperature cycling	Appearance	There must be no mechanical damage.	Based on paragraph 9.3 Number of cycles: 10 Capacitance measured after 24 ± 2 hrs.
	Rate of capacitance change	± 2.5% ± 0.25 pF, whichever is larger.	
	Dissipation factor (tanδ)	Must satisfy initial specified value.	
	Insulation resistance	10,000 MΩ or 500MΩ·μF , whichever is smaller	
Humidity load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9 Test temperature : 40 ± 2ºC Relative humidity : 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs. Capacitance measured after 24 ± 2 hrs.
	Rate of capacitance change	± 7.5% or ± 0.75 pF , whichever is larger.	
	Dissipation factor (tanδ)	0.5% or less	
	Insulation resistance	500 MΩ or 25MΩ·μF, whichever is smaller	
High-temperature load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.10 Test temperature : Max. operating temp. Applied voltage : rated voltage x 200% Test time : 1,000 to 1,048 hrs. Capacitance measured after 24 ± 2 hrs.
	Rate of capacitance change	± 3.0% or ± 0.3 pF , whichever is larger.	
	Dissipation factor (tanδ)	0.3% or less	
	Insulation resistance	1,000 MΩ or 50MΩ·μF , whichever is smaller	

Ceramic capacitors

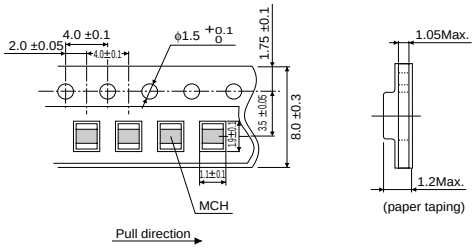
Class 2 (High dielectric constant)

Item \ Temperature characteristics		C,CN (X7R)	F,FN(Y5V)	Test methods / conditions (based on JIS C 5102)
Operating temperature		- 55ºC~ + 125ºC	- 30ºC~ + 85ºC	————
Nominal capacitance (C)		Must be within the specified tolerance range.		Based on paragraph 7.8 Measured at room temperature and standard humidity. Measurement frequency : 1 ± 0.1 kHz Measurement voltage : 1.0 ± 0.2 Vrms.
tan δ		Rated Voltage 50V : 3.0% or less 25V : 3.0% or less	Rated Voltage 50V : 5.0% or less 25V : 7.5% or less 16V : 10.0% or less	
Insulation resistance (IR)		10,000 MΩ or 500MΩ·μF, whichever is smaller. (Rated Voltage 16V,10V : 10,000MΩ or 100MΩ·μF, whichever is smaller.)		Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 ± 5s.
Withstanding voltage		The insulation must not be damaged.		Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measure.
Temperature characteristics		Within ± 15%	Within ± 22, - 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20ºC, with no voltage applied.
Terminal adherence		No detachment or signs of detachment.		Based on paragraph 8.11.2 Apply 5N (0.51 kg · for 10 ± 1s in the direction indicated by the arrow. 
Resistance to vibration	Appearance	There must be no mechanical damage.		Chip is mounted to a board in the manner shown on the right, subjected to vibration (type A in paragraph 8.2), and measured 48 ± 4 hrs. later. 
	Rate of capacitance change	Within ± 7.5%	Within ± 20%	
	Dissipation factor (tan δ)	Must satisfy initial specified value.		
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.		Based on paragraph 8.13 Soldering temperature : 235 ± 5ºC Soldering time : 2 ± 0.5s
Resistance to soldering heat	Appearance	There must be no mechanical damage.		Based on paragraph 8.14 Soldering temperature : 260 ± 5ºC Soldering time : 5 ± 0.5s Preheating : 150 ± 10ºC for 1 to 2 min.
	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	
	Dissipation factor (tan δ)	Must satisfy 2.0 times of initial specified value.	Must satisfy 1.5 times of initial specified value.	
	Insulation resistance	10,000 MΩ or 500MΩ·μF, whichever is smaller. (Rated Voltage 16V,10V : 10,000MΩ or 100MΩ·μF, whichever is smaller.)		
	Withstanding voltage	The insulation must not be damaged.		
Temperature cycling	Appearance	There must be no mechanical damage.		Based on paragraph 9.3 Number of cycles: 5 Capacitance measured after 48 ± 4 hrs.
	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	
	Dissipation factor (tan δ)	Must satisfy 2.0 times of initial specified value.	Must satisfy 1.5 times of initial specified value.	
	Insulation resistance	10,000 MΩ or 500MΩ·μF, whichever is smaller. (Rated Voltage 16V,10V : 10,000MΩ or 100MΩ·μF, whichever is smaller.)		
Humidity load test	Appearance	There must be no mechanical damage.		Based on paragraph 9.9 Test temperature : 40 ± 2ºC Relative humidity : 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs. Capacitance measured after 48 ± 4 hrs.
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	
	Dissipation factor (tan δ)	Must satisfy 2.0 times of initial specified value.	Must satisfy 1.5 times of initial specified value.	
	Insulation resistance	500 MΩ or 25MΩ·μF, whichever is smaller. (Rated Voltage 16V,10V : 500MΩ or 5MΩ·μF, whichever is smaller.)		
High-temperature load test	Appearance	There must be no mechanical damage.		Based on paragraph 9.10 Test temperature : Max. operating temp. Applied voltage : rated voltage Test time : 1,000 to 1,048 hrs. Capacitance measured after 48 ± 4 hrs.
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	
	Dissipation factor (tan δ)	Must satisfy 2.0 times of initial specified value.	Must satisfy 1.5 times of initial specified value.	
	Insulation resistance	1,000 MΩ or 50MΩ·μF, whichever is smaller. (Rated Voltage 16V,10V : 1,000MΩ or 10MΩ·μF, whichever is smaller.)		

●Packaging specifications

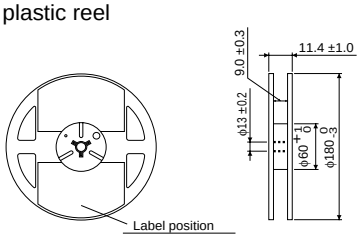
(Units : mm)

Taping

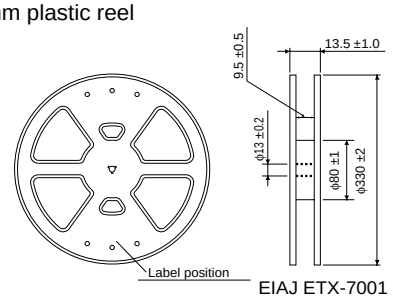


Reel

ϕ180 mm plastic reel

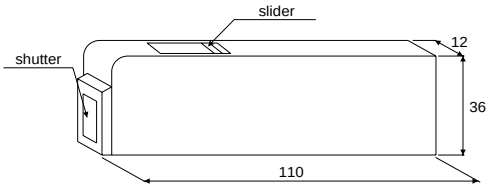


ϕ330 mm plastic reel



EIAJ ETX-7001 compliant

Bulk case



EIAJ ET-7201A compliant

MCH18	15,000pcs / case

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●Electrical characteristics

■ A (C0G) Characteristics

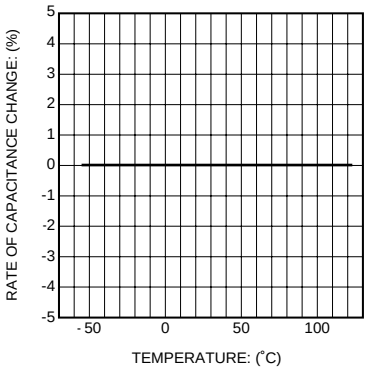

Fig.1 Capacitance - temperature characteristics

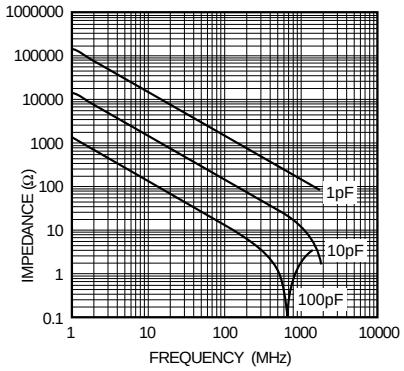

Fig.2 Impedance - frequency characteristics

■C (X7R) Characteristics

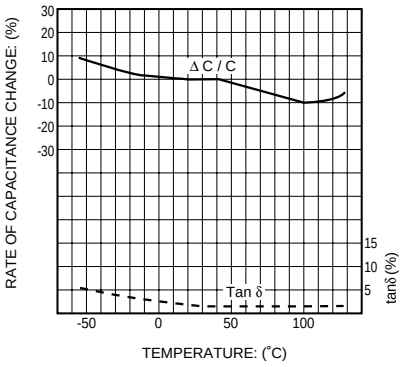

Fig.3 Capacitance - temperature characteristics

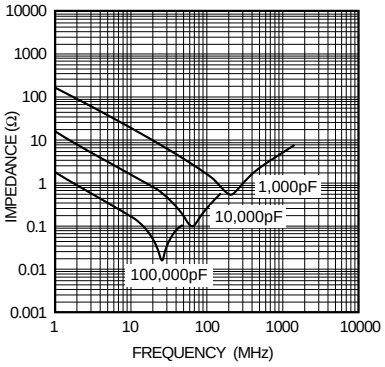

Fig.4 Impedance - frequency characteristics

■F (Y5V) Characteristics

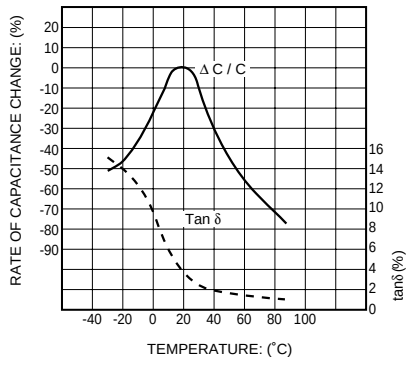

Fig.5 Capacitance - temperature characteristics

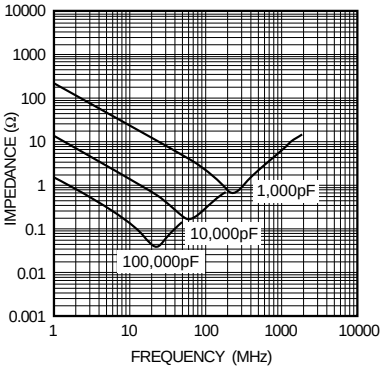

Fig.6 Impedance - frequency characteristics

■ Temperature cycling test

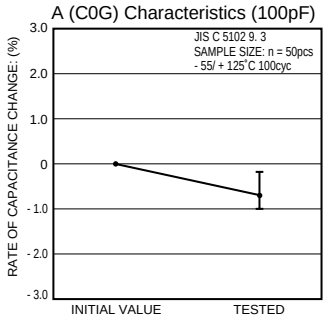

Fig.7 Rate of capacitance change

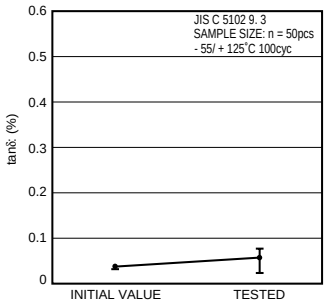

Fig.8 Tanδ

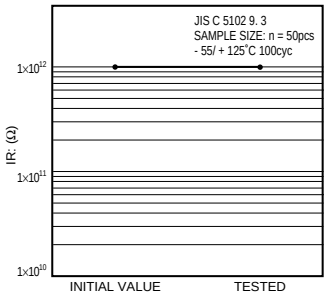

Fig.9 Insulation resistance

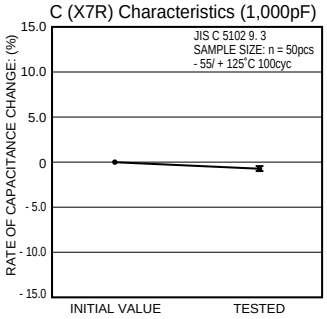

Fig.10 Rate of capacitance change

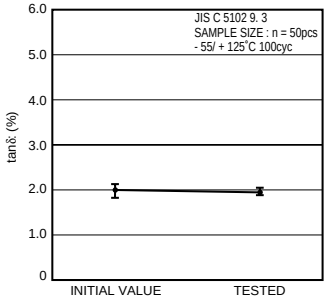

Fig.11 Tanδ

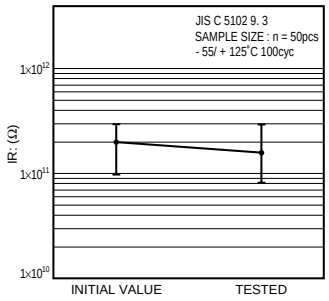

Fig.12 Insulation resistance

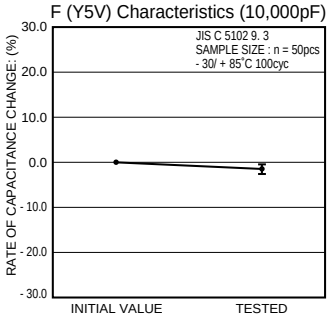

Fig.13 Rate of capacitance change

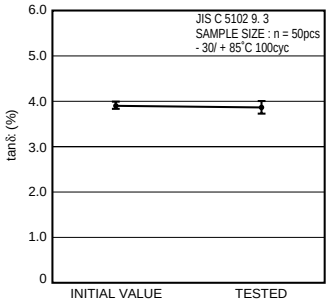

Fig.14 Tanδ

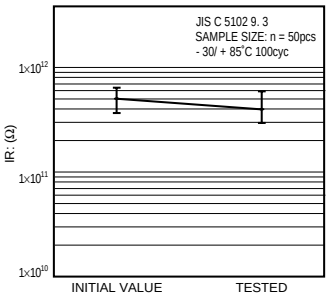

Fig.15 Insulation resistance

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■ High-temperature load test

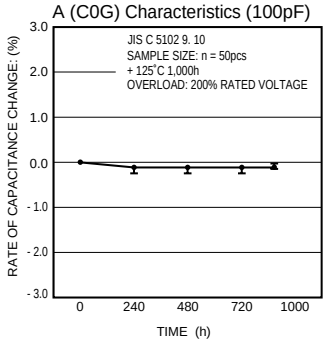

Fig.16 Rate of capacitance change

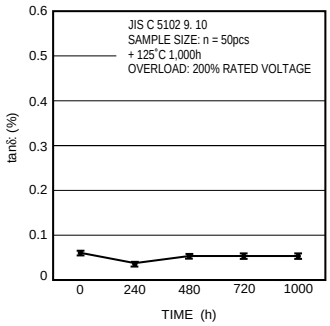

Fig.17 Tanδ

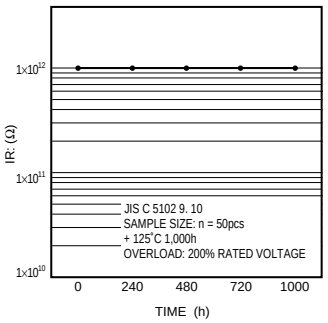

Fig.18 Insulation resistance

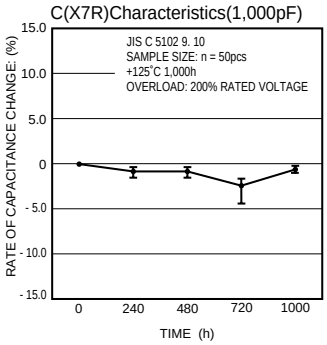

Fig.19 Rate of capacitance change

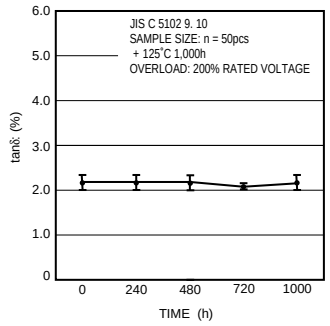

Fig.20 Tan δ

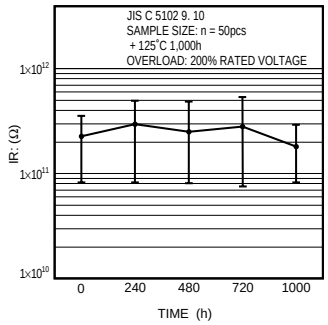

Fig.21 Insulation resistance

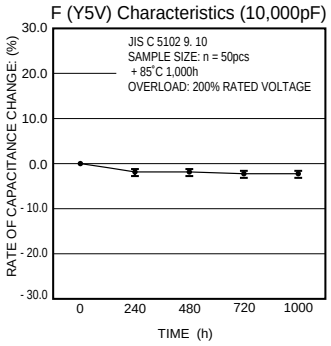

Fig.22 Rate of capacitance change

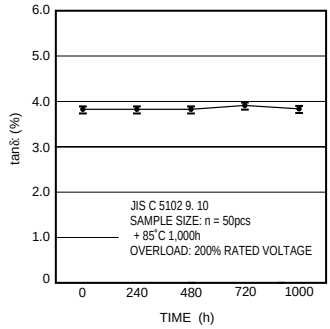

Fig.23 Tanδ

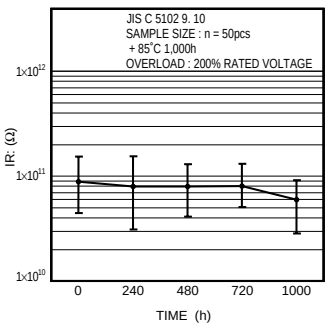

Fig.24 Insulation resistance

■ Humidity load test

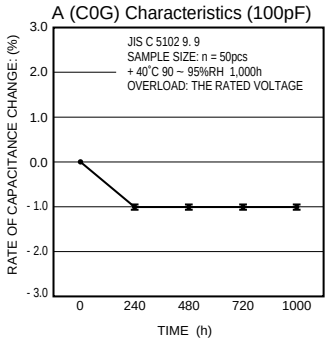

Fig.25 Rate of capacitance change

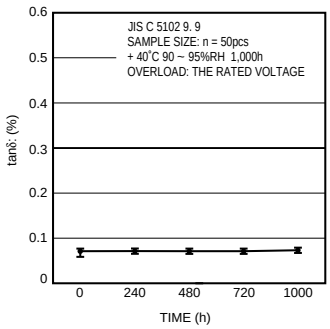

Fig.26 Tan δ

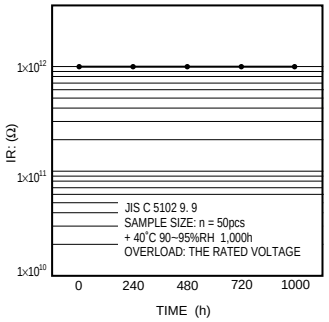

Fig.27 Insulation resistance

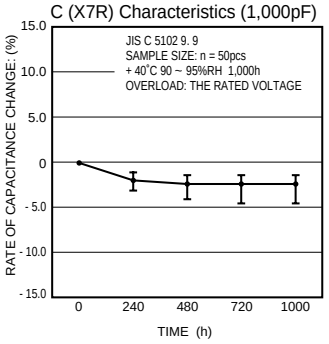

Fig.28 Rate of capacitance change

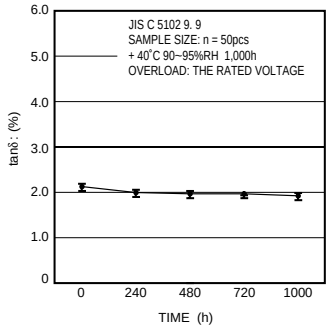

Fig.29 Tanδ

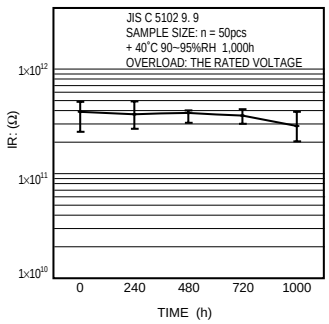

Fig.30 Insulation resistance

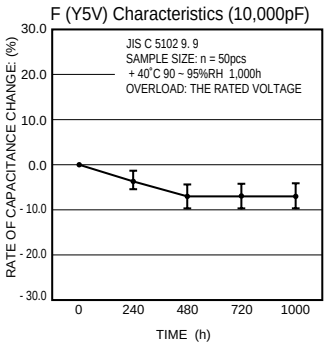

Fig.31 Rate of capacitance change

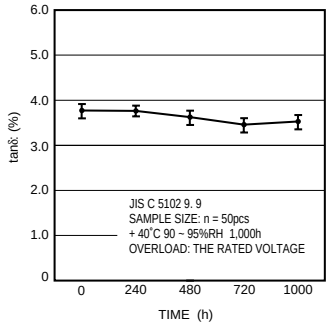

Fig.32 Tanδ

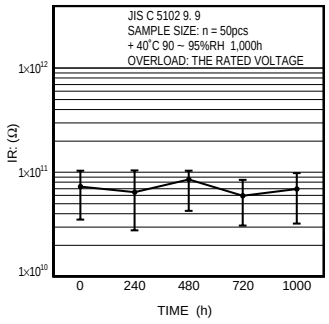

Fig.33 Insulation resistance